

Search Notes

Application/Control No.

10/632,554

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

TAKANO ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	updated	8/16/2005	SWH
400	updated	8/16/2005	SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
347	37,8	8/16/2005	SWH
400	59	8/16/2005	SWH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR